

**e-Diagnostic Working Group Meeting Attendance - September 20, 2000  
International Sematech**

<b>Company</b>	<b>Name</b>	
Advanced Energy Industries	Bill	Shade
Adventa Control	Richard	Beaver
Adventa Control	Carl	Fiorletta
AMD	Michael	Borman
AMD	Eric	Christensen
AMD	Greg	Nelson
Applied Materials	Shay	Assaf
Applied Materials	Juan	Bocanegra
Applied Materials	Neil	Frank
ASYST Technologies	Chris	Barbazette
ASYST Technologies	Paul	Steele
AvantCom Network	Bob	Chamberlain
AvantCom Network	Subhash	Patankar
Axcelis Technologies Inc.	Frank	D'Andrea
Axcelis Technologies Inc.	Hans	Sundstrom
Axcelis Technologies Inc.	Han	Zhang
Brooks Automation	Chris	Brandson
Canon	Arthur	Luk
Domain Logix	Lawrence	Eng
Electroglas, Inc.	Howard	Ignatius
General Electric	Ujjal	Basu
General Electric	Tim	Johnson
HP	Glen	Ingebrigtsen
IBM	William	Ramus
IBM/ISMT	John	Pace
Intel	David	Bloss
Intel	Jonathan	Clemens
Intel	Kacey	Crowley
Intel	Wane	Dompier
Intel	Piero	Fioravanti
Intel	James	Martin
Intel	Anant	Raman
International Sematech	Scott	Kramer
International Sematech	Carol	MacNaughton
International Sematech	Peter	Marrone
International Sematech	Mary	Marsden
International Sematech	Margaret	Pratt
International Sematech	Mike	Sigman
International Sematech	Harvey	Wohlwend
IPC	Nicole	Richter-Ulmer
IPC	Gerhard	Rupp
KLA-Tencor	Roger	Eastvold
KLA-Tencor	Michael	Locy
KLA-Tencor	Nick	Nikolic
KLA-Tencor	Anjali	Sridhar
Kokusai	Tom	Marrone
Lam Research Corporation	Jacques	Matteau
Motorola	Don	Hartman
Nikon Precision, Inc.	Sean	McNamara

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<b>Company</b>		<b>Name</b>
Nikon Precision, Inc.	John	Wiesner
Novellus	Tomas	Garley
PRI Automation, Inc.	Larry	Dulmage
Schlumberger	Claude	Baudoin
Schlumberger	Robert	Brandom
Schlumberger	Chris	Stambaugh
Semy Engineering	Muthu	Ramalingam
SISA	John	Ellis
STM/ISMT	Olivier	Louveau
SVG	Peter	DelMastro
Symphony Systems	Keith	Bennett
Teradyne Inc	Frank	Kennedy
Teradyne Inc	Gerry	McMahon
Tokyo Electron America, Inc.	Lou	Steen

*Information Based on Registered Sign-in 9/20/2000*